### ICDD Crystallographic Scholarship Awards

#### **International Centre for Diffraction Data Crystallography Scholarship Awards**

The science of crystallography has played a key role in the development of X-ray diffraction, electron diffraction and neutron diffraction for the elucidation of the atomic structure of matter. Crystallography is an interdisciplinary branch of science taught in departments of physics, chemistry, geology, molecular biology, metallurgy, and materials science. To encourage promising graduate students to pursue crystallographically-oriented research, the International Centre has established a Crystallography Scholarship Fund. While the Ewald Prize is awarded every three years to an internationally recognized crystallographer, little effort has been made by science departments to cultivate aspiring crystallographers. Convinced of the beneficial, scientific impact of the proposed scholarships for crystallographically-oriented research, the ICDD Chairman has solicited funds from private and industrial sectors to reach the goal of \$250,000. Approximately one-half of this goal has been reached. The ICDD has awarded two scholarships for the calendar year 1992 and intends to award two additional scholarships in 1993.

Qualifications for the applicants: A graduate student with major interest in crystallography (crystal structure analysis, crystal morphology, modulated structures, correlation of atomic structure with physical properties, systematic classification of crystal structures, phase identification and materials characterization). There are no restrictions on country, race, age, or sex. The term of the scholarship is one year with one renewal if applied for by the recipient and if approved by the ICDD at the end of the first year on

the basis of the student's written accomplishments during the first year.

#### Submit:

- a. A one-page proposal by the graduate student describing the type of crystallographic research to be partially supported by scholarship.
- b. A supportive letter from the sponsoring professor of an accredited university or an institute of technology.

#### Restrictions on the scholarship fund:

- a. The scholarship stipend of \$2,000 is to be used by the graduate student to help defray tuition and laboratory fees. A portion of the stipend may be applied to registration fees to accredited scientific meetings related to crystallography.
- b. No more than one scholarship will be awarded to any one accredited institution per year.
- c. The funds of the scholarship are not to be used for travel.

The awarding of the scholarships shall be administered by a committee consisting of the ICDD Chairman, the Chairman of the ICDD Technical Committee, and the Chairman of the ICDD Education Subcommittee. One or more accredited professors (with no conflicts of interest) may be invited to assist in the selection of successful candidates.

Applications should be mailed, prior to 31 October 1992, to:

Secretary, International Centre for Diffraction Data 1601 Park Lane

Swarthmore, PA 19081-2389, USA



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For details write or call Mary M. Rossi, Advertising Manager, Powder Diffraction. ICDD, 1601 Park Lane, Swarthmore, Pennsylvania 19081 215-328-9403 FAX 215-328-2503

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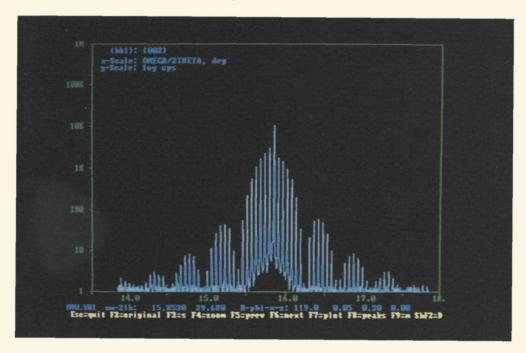
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